## Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/594,282	ISHII ET AL.	
Examiner	Art Unit	
Sin J. Lee	1795	

SEARCHED					
Class	Subclass	Date	Examiner		

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
,	DATE	EXMR		
EIC Structure searches for claims 18, 35 and 38.	11/3/2008	SJL		
East text search	11/3/2008	SJL		